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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): JIN et al.

Serial No.: 09/621,717

Filed: July 24, 2000

Title: Structure and Method for Monitoring  
a Semiconductor Process, and Method  
of Making Such a Structure

Attorney Docket No.: CY-0013

Group Art Unit: 2822

Examiner: Thomas, T.

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## RESPONSE TO FINAL OFFICE ACTION

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

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A. Introductory Comments

The following is submitted in response to the FINAL Office Action dated November 18, 2003. The two month Advisory Action period ends January 19, 2004.

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37 C.F.R. §1.8

I hereby certify that this correspondence is being

30 ☒ transmitted via facsimile to the United States Patent and Trademark Office to fax number: 1-703-872-9306Date of Transmittal: JANUARY 5, 2004

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P.O. Box 1450, Alexandria VA 22313-1450.

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Date of Deposit: \_\_\_\_\_

Typed/Printed Name: Bradley T. Sako

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Signature: Bradley T. Sako

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**B. Amendments to the Specification.**

There are no current amendments to the Specification.

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